



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re patent application of  
Bernard Fay et al.

Serial No.: 09/881,026

Group Art Unit: Not Known

Filed: June 15, 2001

Examiner: Not Known

For: AUTOMATED OVERLAY METROLOGY SYSTEM

Commissioner of Patents and Trademarks  
Washington, D.C. 20231

## PRELIMINARY AMENDMENT

Sir:

Prior to an official action on the merits of the  
above-identified application, please amend the  
application as follows:

In the specification:

Please substitute the following paragraphs for the  
paragraphs of the application as originally filed at  
the locations respectively indicated. A marked-up copy  
of these requested changes is provided as an appendix  
to this preliminary amendment.

Page 14, line 15+:

61  
A simulation of the FFT amplitude variation of  
spectral reflectance data from the pattern of Figure 2A  
is shown in Figure 3 and a simulation of FFT amplitude  
variation of spectral reflectance data from the pattern  
of Figure 2B is shown in Figure 4. It is assumed for  
purposes of this discussion that the differently shaded  
portions 22, 24 of Figure 2A (and 2B) have different  
reflectivity and that the marks include at least one

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TC 1700